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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants

: Hideaki KAWAMURA et al.

Group Art Unit: Not Yet Assigned

Appl. No.

: 10/509,678 \

(U.S. National Stage of PCT/JP03/5557)

**Examiner: Not Yet Assigned** 

I.A. Filed

: April 30, 2003

For

: PICTURE ANGLE DETECTION APPARATUS AND SCANNING

LINE INTERPOLATIONDEVICE HAVINGTHE SAME

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents
U.S. Patent and Trademark Office
220 20th Street S.
Customer Window, Mail Stop AMENDMENT
Crystal Plaza Two, Lobby, Room 1B03
Arlington, VA 22202

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby submit a copy of an International Search Report that was mailed on August 12, 2003, with respect to International Patent Application No. PCT/JP03/5557, of which the present application is the U.S. National Stage Application, in which the following documents were cited:

Japanese Laid-Open Patent Publication No. HEI 11-146346, together with an English language Abstract and partial English language translation of the same;

Japanese Laid-Open Patent Publication No. 2000-253238, together with an English language Abstract and partial English language translation of the same;

Japanese Laid-Open Patent Publication No. 2003-52023, together with patent family member International Application No. WO 02/48965 and U.S. Patent Application Publication No. 2003/0011708;

Japanese Laid-Open Patent Publication No. HEI 5-153562, together with patent family member U.S. Patent No. 5,347,599;

Japanese Laid-Open Patent Publication No. HEI 11-41565, together with an English language Abstract of the same; and

Japanese Laid-Open Patent Publication No. HEI 11-331773, together with an English language Abstract of the same.

The category of relevance, pertinent portions, and claims to which each document is relevant, as ascertained by the Japanese Examiner are set forth in the International Search Report.

Applicants also bring to the Examiner's attention the following documents:

Japanese Laid-Open Patent Publication No. HEI 9-37214, together with patent family members U.S. Patent No. 5,886,745 and U.S. Patent No.

5,796,437. Applicants note that the Japanese patent document is cited on page 2 of the specification of the present application; and

Japanese Laid-Open Patent Publication No. HEI 2-213289, together with an English language Abstract of the same.

Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patents and U.S. patent application publication are not enclosed herewith. However, if any copies are needed, the Examiner is respectfully requested to contact the undersigned.

P26093.A01

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents are attached hereto and all of the documents are listed on the attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Applicants note that an Office Action on the merits has not issued in the present application, and thus no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully Submitted, Hideaki KAWAMURA et al.

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January 10, 2005 GREENBLUM & BERNSTEIN, P.L.C. 1950 Roland Clarke Place Reston, VA 20191 (703) 716-1191 FORM PTO-1449

## U.S. Department of Commerce Patent and Trademark Office

Atty.	Docket No.	
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Application No. 10/509,678

## **Applicant** INFORMATION DISCLOSURE STATEMENT Hideaki KAWAMURA et al. BY APPLICANT (Use several sheets if necessary) Filing Date Group I.A. Filed April 30, 2003 Not Yet Assigned **U.S. PATENT DOCUMENTS** FILING DATE **EXAMINER** IF **DOCUMENT NUMBER** INITIAL DATE NAME **CLASS SUBCLASS APPROPRIATE** 2003 / 1 1 0 01/16/03 KAWAMURA et al. 0 0 5 7 5 3 4 9 9 09/13/94 YAMASHITA et al. 5 8 8 6 7 4 5 03/23/99 MURAJI et al. 7. 9 6 4 3 7 MURAJI et al. 08/18/98 **FOREIGN PATENT DOCUMENTS TRANSLATION SUBCLASS DOCUMENT NUMBER** DATE COUNTRY CLASS YES NO 11 1 4 6 3 4 05/28/99 **JAPAN** Χ 2000 2 5 3 2 3 8 09/14/00 **JAPAN** Χ \_ 2003 0 5 2 0 2 3 02/21/03 **JAPAN** \_ 2 4 8 9 6 5 06/20/02 W.I.P.O. 0 1 5 1 5 3 5 6 2 06/18/93 **JAPAN** 1 5 6 11 0 4 5 02/12/99 **JAPAN** 7 7 11 3 3 1 3 11/30/99 **JAPAN** 9 3 7 2 1 4 02/07/97 **JAPAN** 2 2 **JAPAN** 2 1 3 8 9 08/24/90 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) 1 English Language Abstract of JP 11-146346. 2 English Language Abstract of JP 2000-253238. 3 English Language Abstract of JP 11-041565. 4 English Language Abstract of JP 11-331773. English Language Abstract of JP 2-213289. **EXAMINER** DATE CONSIDERED

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.